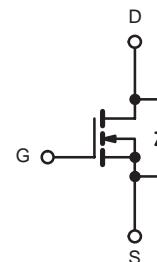
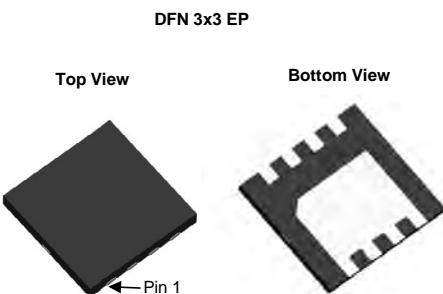


## N-Channel 30-V (D-S) MOSFET

VDS	30	V
RDS(on),typ	VGS=10V	13 mΩ
RDS(on),typ	VGS=4.5V	19 mΩ
ID	30 A	

## FEATURES

- Halogen-free
- TrenchFET® Power MOSFET
- 100 % R<sub>g</sub> and UIS Tested



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS  $T_A = 25^\circ\text{C}$ , unless otherwise noted

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	
Continuous Drain Current ( $T_J = 150^\circ\text{C}$ )	$I_D$	30	A
		20	
		21.5 <sup>b, c</sup>	
		17.1 <sup>b, c</sup>	
Pulsed Drain Current	$I_{DM}$	100	A
Continuous Source-Drain Diode Current	$I_S$	13	
		3.1 <sup>b, c</sup>	
Single Pulse Avalanche Current	$I_{AS}$	10	mJ
Avalanche Energy	$E_{AS}$	5	
Maximum Power Dissipation	$P_D$	60	W
		30	
		3.7 <sup>b, c</sup>	
		2.4 <sup>b, c</sup>	
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	- 55 to 150	°C

## THERMAL RESISTANCE RATINGS

Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient <sup>b, d</sup>	$t \leq 10\text{ s}$	$R_{thJA}$	27	°C/W
Maximum Junction-to-Foot (Drain)	Steady State	$R_{thJF}$	6	

Notes:

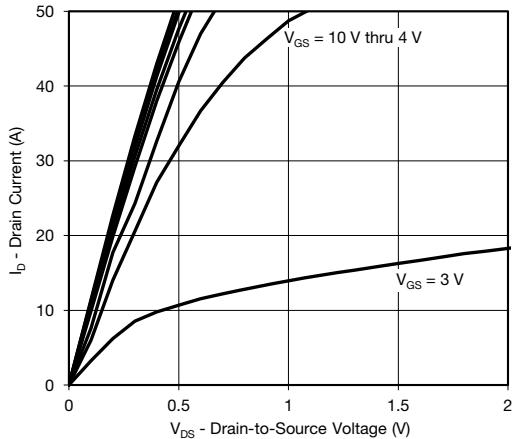
- Based on  $T_C = 25^\circ\text{C}$ .
- Surface Mounted on 1" x 1" FR4 board.
- $t = 10\text{ s}$ .
- Maximum under Steady State conditions is 85 °C/W.

<b>SPECIFICATIONS</b> $T_J = 25^\circ\text{C}$ , unless otherwise noted							
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit	
<b>Static</b>							
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	30			V	
$V_{DS}$ Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250 \mu\text{A}$		27		mV/ $^\circ\text{C}$	
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$			- 5.6			
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	1.0		3.0	V	
Gate-Source Leakage	$I_{GSS}$	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			$\pm 100$	nA	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	$\mu\text{A}$	
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$			10		
On-State Drain Current <sup>a</sup>	$I_{D(\text{on})}$	$V_{DS} \geq 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			A	
Drain-Source On-State Resistance <sup>a</sup>	$R_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 15 \text{ A}$		13		$\text{m}\Omega$	
		$V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		19			
Forward Transconductance <sup>a</sup>	$g_{fs}$	$V_{DS} = 15 \text{ V}, I_D = 15 \text{ A}$		75		S	
<b>Dynamic<sup>b</sup></b>							
Input Capacitance	$C_{iss}$	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$			900	pF	
Output Capacitance	$C_{oss}$				236		
Reverse Transfer Capacitance	$C_{rss}$				20		
Total Gate Charge	$Q_g$	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$			20	nC	
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$			9		
Gate-Drain Charge	$Q_{gd}$				2.1		
Gate Resistance	$R_g$				0.7		
Turn-On Delay Time	$t_{d(\text{on})}$	$V_{DD} = 15 \text{ V}, R_L = 1.5 \Omega$ $I_D \approx 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		0.2	1.1	2.2	$\Omega$
Rise Time	$t_r$				8	16	ns
Turn-Off Delay Time	$t_{d(\text{off})}$				16	30	
Fall Time	$t_f$				17	35	
Turn-On Delay Time	$t_{d(\text{on})}$				7	15	
Rise Time	$t_r$				14	30	
Turn-Off Delay Time	$t_{d(\text{off})}$				50	100	
Fall Time	$t_f$				16	30	
					8	18	
<b>Drain-Source Body Diode Characteristics</b>							
Continuous Source-Drain Diode Current	$I_S$	$T_C = 25^\circ\text{C}$			13	A	
Pulse Diode Forward Current <sup>a</sup>	$I_{SM}$				100		
Body Diode Voltage	$V_{SD}$	$I_S = 3 \text{ A}$			1.2	V	
Body Diode Reverse Recovery Time	$t_{rr}$	$I_F = 10 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$			40	ns	
Body Diode Reverse Recovery Charge	$Q_{rr}$				20		
Reverse Recovery Fall Time	$t_a$			12.5			
Reverse Recovery Rise Time	$t_b$			7.5			

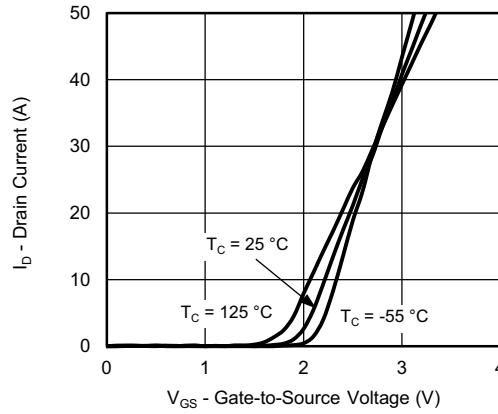
Notes:

- a. Pulse test; pulse width  $\leq 300 \mu\text{s}$ , duty cycle  $\leq 2\%$
- b. Guaranteed by design, not subject to production testing.

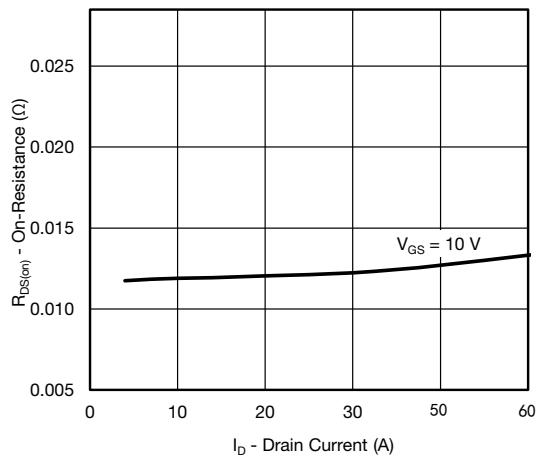
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted

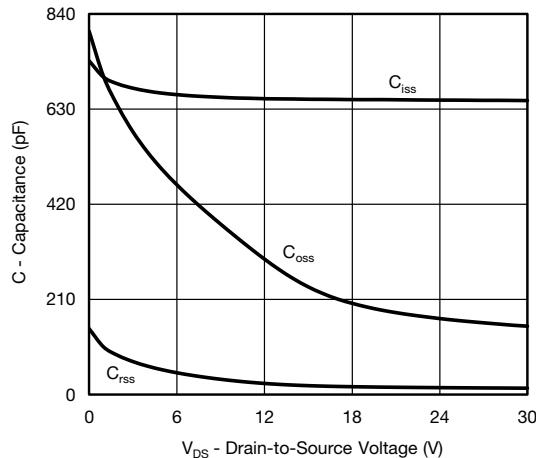
Output Characteristics



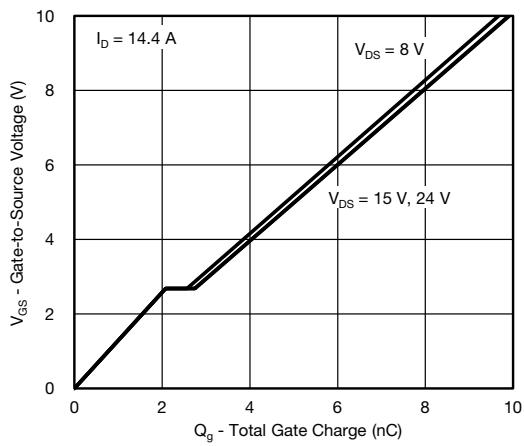
Transfer Characteristics



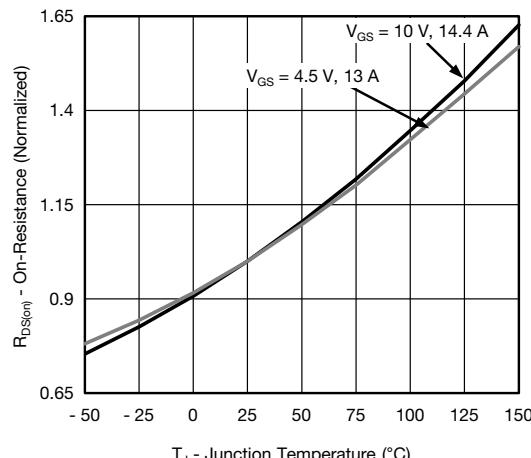
On-Resistance vs. Drain Current



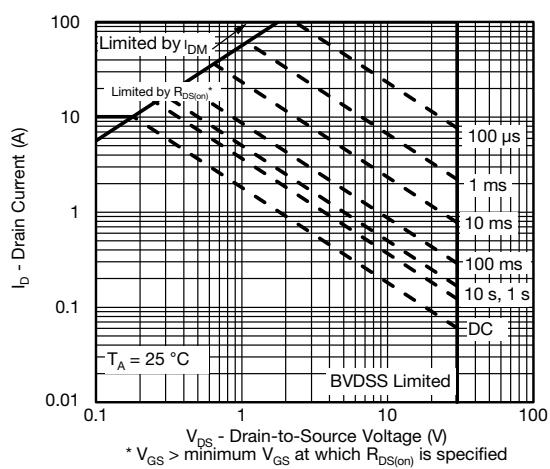
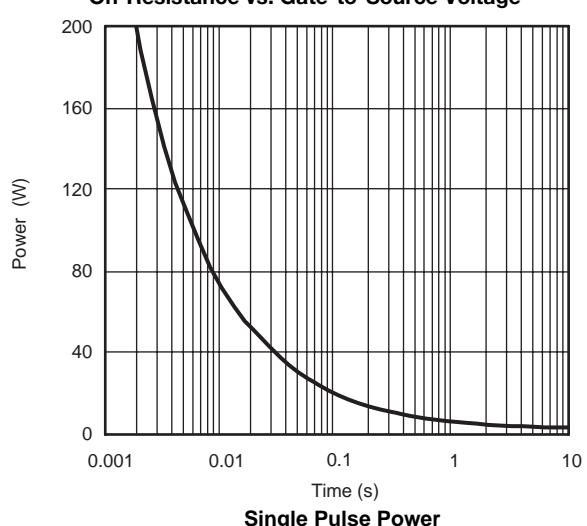
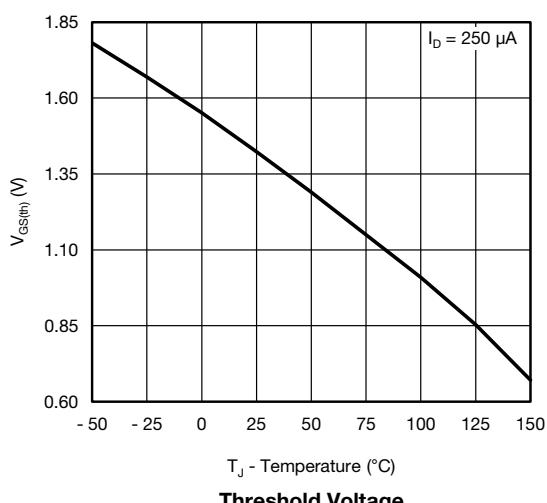
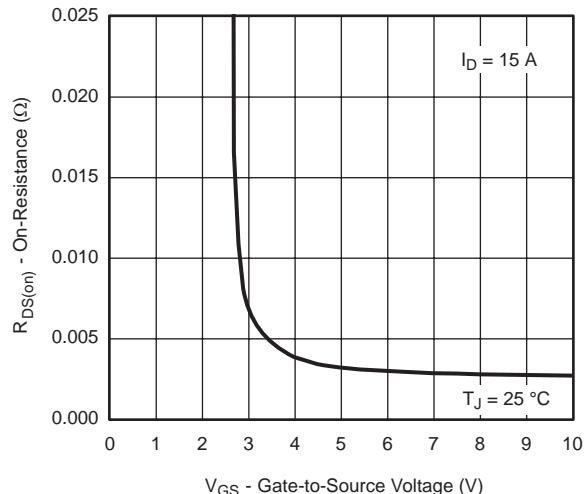
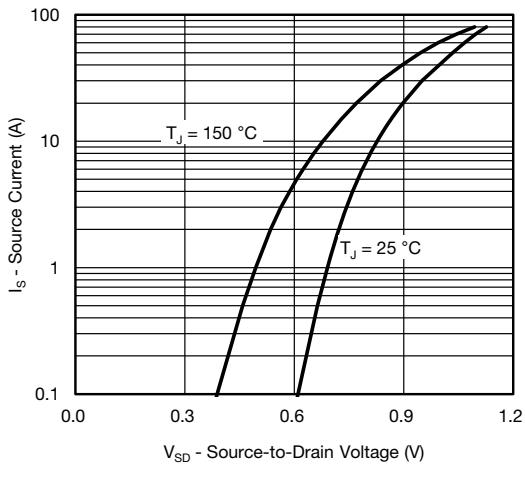
Capacitance

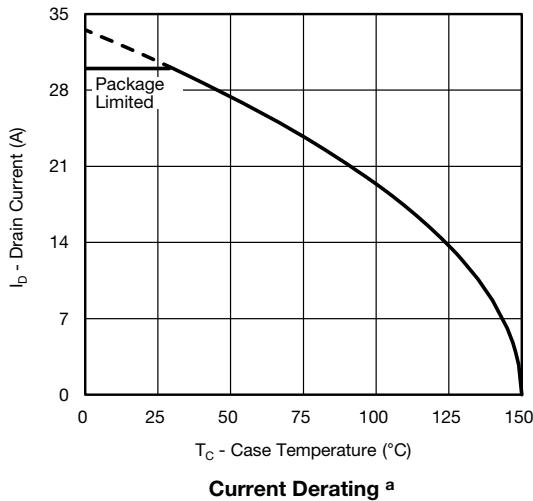
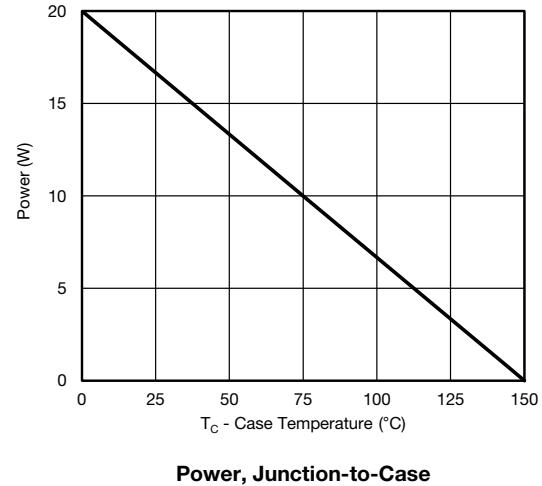


Gate Charge

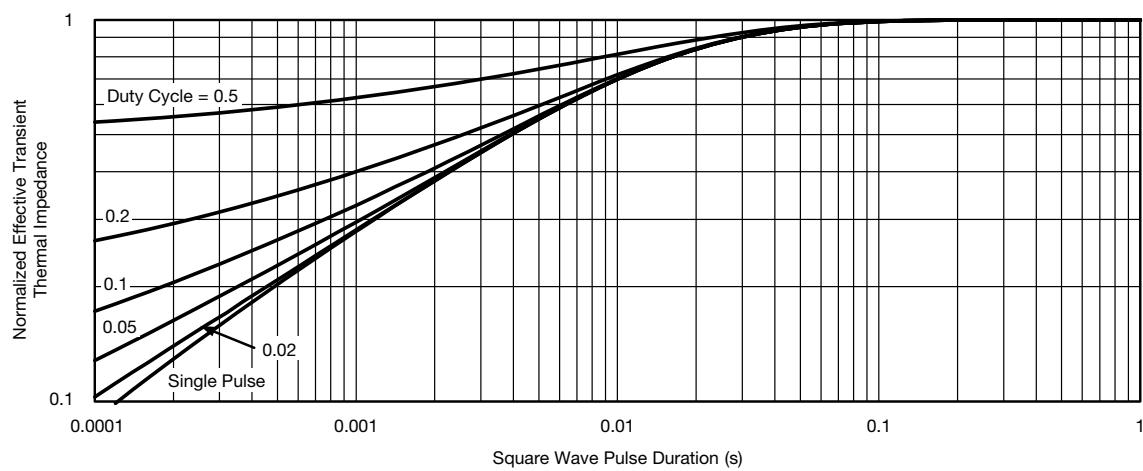
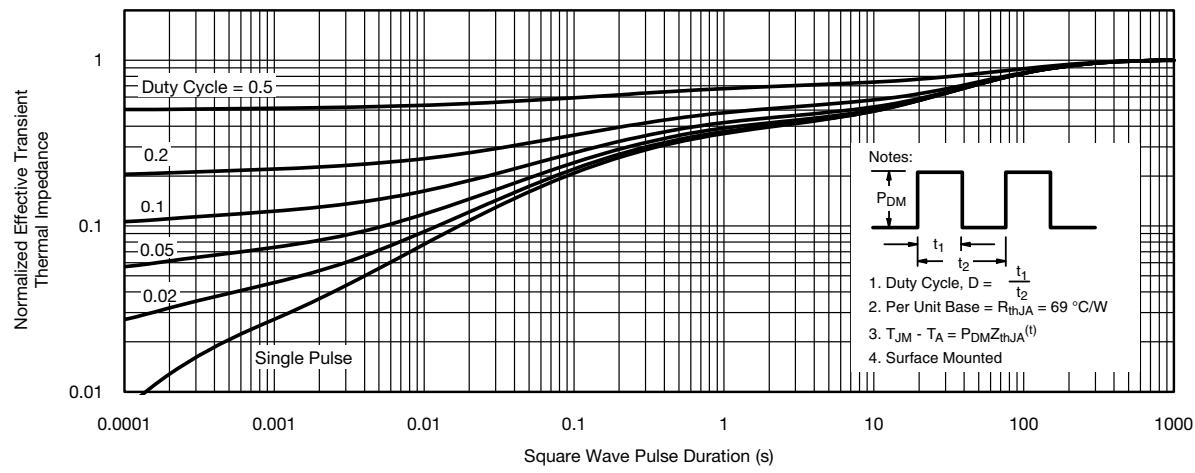


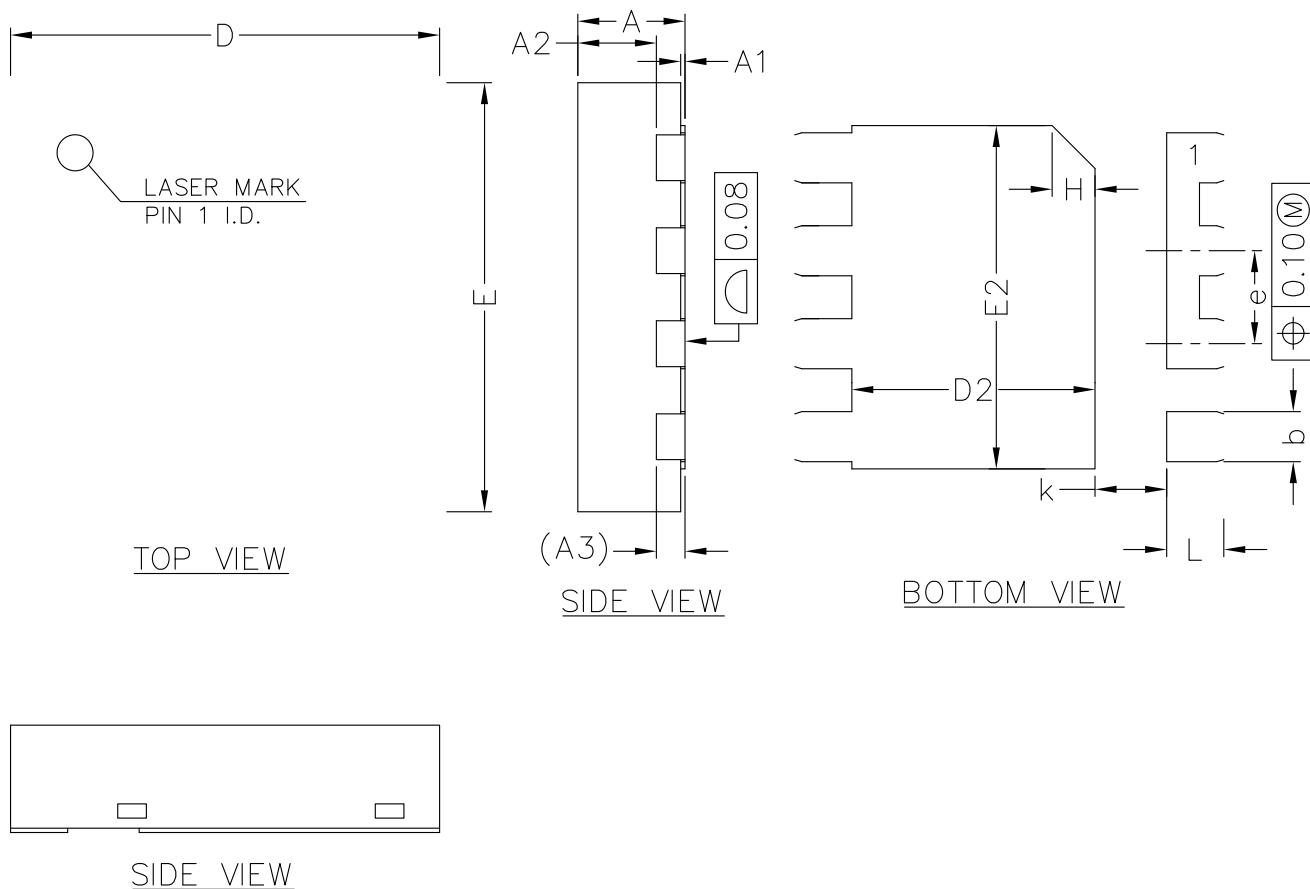
On-Resistance vs. Junction Temperature

**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted

**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted
**Current Derating <sup>a</sup>****Power, Junction-to-Case****Note**

- a. The power dissipation  $P_D$  is based on  $T_J$  max. = 25 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted



COMMON DIMENSIONS  
(UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX
A	0.70	0.75	0.80
A1	0.00	0.02	0.05
A2	0.50	0.55	0.60
A3	0.20REF		
b	0.30	0.35	0.40
D	2.90	3.00	3.10
E	2.90	3.00	3.10
D2	1.60	1.70	1.80
E2	2.30	2.40	2.50
e	0.55	0.65	0.75
K	0.40	0.50	0.60
L	0.35	0.40	0.45